

Velox™ 3.4.1 Highlights

Probe Station Control Software

The most powerful engineering software in the market

With the latest Velox 3.4.1 update your Probe Station becomes more reliable and versatile. We have optimized the ReAlign algorithm to improve the detection of pyramid probe cards. New is the support of probes with MEMS Tip. And there are more optimizations.

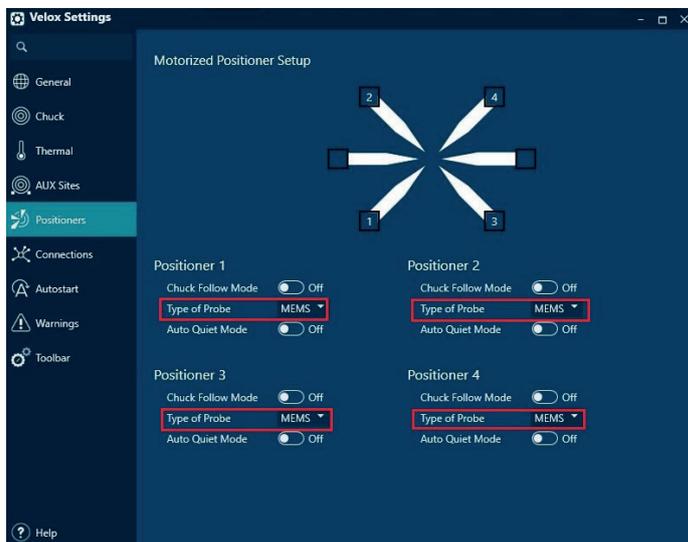
A free Velox 3.4.1 upgrade is available for existing customers.*



Spectrum Vision enhancements

New DCP-X probes support

- / With the new selection option (MEMS) a training algorithm is selected specifically for the new DCP-X probes.
- / The new algorithm integrated in the Autonomous Assistant enables easy training of the probes and reliable image recognition.



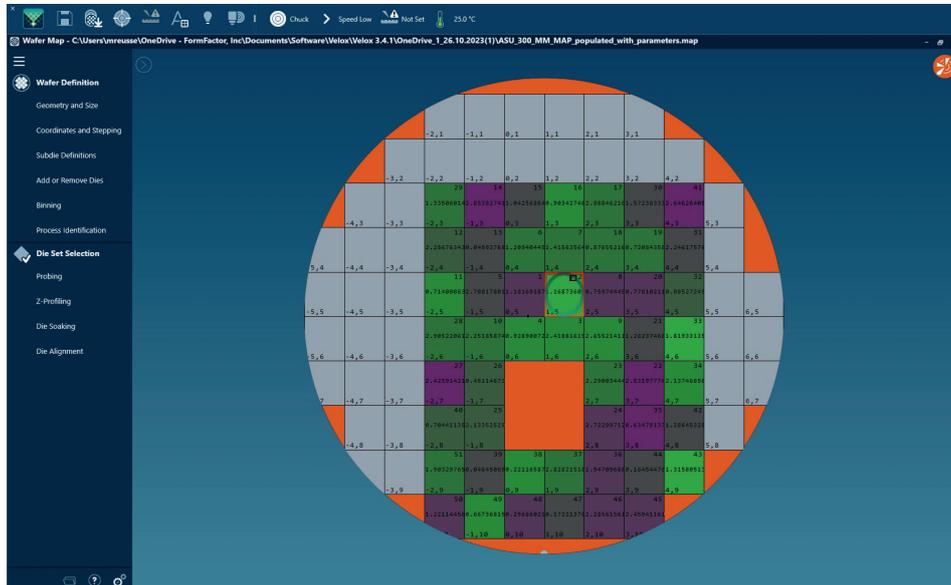
Pyramid Probe Cards

- / For ReAlign training of pyramid probe cards with rectangular needle arrangement, probe markers 3 and 4 have been added to improve probe to pad reliability.

Wafer Map enhancements

Add support for Binning rules (similar to Bin Auto Selection)

Parametric mapping is back and has been drastically improved over the previous version. The parameter setup has become more intuitive. With the new binning function, the test parameters are displayed directly in the wafer map and can be saved in the wafer map file. In addition, a sub binning statistic can be displayed during the test process.



Motorized Positioner Layouts

/ Individual and fully customizable positioner layouts can be defined and saved. These individual layouts can be called up via Remote Command. This eliminates the need for complex programming of the Test Executive.

SubDie handling

/ SubDie layouts can now be imported or exported via CSV file.

General

Station Verifier

- / Added checks for Scope and Positioner configuration.
- / Add check for Probe Station Controller version compatibility.
- / Add TCP Delay check for correct network settings to controller.

** Requires Service visit. Please contact your local sales person for more information.*